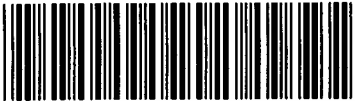


<b>Search Notes</b>  	<b>Application/Control No.</b>  09925397	<b>Applicant(s)/Patent Under Reexamination</b>  CHANG ET AL.
	<b>Examiner</b>  Ehichioya, Fred I	<b>Art Unit</b>  2162

<b>SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

<b>SEARCH NOTES</b>		
<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
IEEE Xplore	12/16/07	FE
East (US-PGPub, USPat, EPO, JPO, Derwent).text search only	12/17/07	FE

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>